7/19/2012

RELIABILITY MONITOR REPORT
FOR

San Antonio Silicon Gate 0.8µm CMOS EEPROM (EB8)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX1781ETM+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 8720 QUANTITY: 45 FAILS: 0 FITS: 13.1

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 7/1/2011 and 6/30/2012 .

Process Information:

Process Description: San Antonio Silicon Gate 0.8µm CMOS EEPROM (EB8)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1132	MAX1781ETM+	135C	1000 HRS	45	0	TML5AA1Z1Q2
				Total:		**0**	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1132	MAX1781ETM+	150C	1000 HRS	77	1	TML5AA1Z1Q2
				Total:		**1**	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1132	MAX1781ETM+	-65C TO 150C	1000 CYS	76	0	TML5AA1Z1Q2
TEMP CYCLE, 5' RAMP, 10' DWELL	1132	MAX1781ETM+	-65C TO 150C	1000 CYS	77	1	TML5AA1Z1Q3
				Total:		**1**	

TEMPERATURE HUMIDITY BIAS

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
BIASED MOISTURE	1132	MAX1781ETM+	130C, 85% R.H.	500 HRS	30	1	TML5AA1Z1Q3
				Total:		**1**	

FAILURE RATE: MTTF (YRS): 8720 QUANTITY: 45 FAILS: 0 FITS: 13.1